

Application/Control No.	Applicant(s)/Patent us Reexamination	nder
09/658,241	HOHNSTEIN ET AL.	
Examiner	Art Unit .	
TAN TRINH	2618	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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